Nuclear Instruments and Methods in Physics Research B 184 (2001) 661–666

ELSEVIER

NIM B
Beam Interactions with Materials & Atoms

www.elsevier.com/locate/nimb

Author index

Abidi, S., see Richard-Viard, M. ... 184 (2001) 490
Altemus, R., see Huston, A.L. ... 184 (2001) 55
Amaldi, U., see Brahme, A. ... 184 (2001) 569
Andò, L., see Torrisi, L. ... 184 (2001) 327
Apel, P.Yu., Yu.E. Korchev, Z. Siwy, R. Spohr and M. Yoshida, Diode-like single-ion track membrane prepared by electro-stopping ... 184 (2001) 337
Araújo, D., see Barbadillo, L. ... 184 (2001) 361
Arimoto, Y., see Yonehara, K. ... 184 (2001) 391
Arora, B.M., see Nair, G.P. ... 184 (2001) 515
Aslanoglou, X.A., see Kokkoris, M. ... 184 (2001) 319
Avila, O., see Horowitz, Y.S. ... 184 (2001) 85

Bajeat, O., see Maunoury, L. ... 184 (2001) 441
Banerjee, S., see Li, D. ... 184 (2001) 500
Barbadillo, L., M.J. Hernández, M. Cervera, P. Rodríguez, J. Piqueras, S.I. Molina, F.M. Morales and D. Araújo, Structural characterization of high-dose $C^+ + N^+$ ion-implanted (1 1 1) Si ... 184 (2001) 361
Barthe, J., Electronic dosimeters based on solid state detectors ... 184 (2001) 158
Bateman, J.E., A new model for electron ranges in solid materials ... 184 (2001) 478
Baumann, T., M.J. Chromik, R.R.C. Clement, C. Freigang, P. Heckman, J.P. Seitz, B.M. Sherrill, M. Thoennessen and E.J. Tryggestad, Catching energetic heavy-ion beams in gas ... 184 (2001) 473
Belyaev, G., see Gardès, D. ... 184 (2001) 458
Bénazeth, C., see Richard-Viard, M. ... 184 (2001) 490
Benoit-Cattin, P., see Richard-Viard, M. ... 184 (2001) 490
Benton, E.R. and E.V. Benton, Space radiation dosimetry in low-Earth orbit and beyond ... 184 (2001) 255
Benton, E.V., see Benton, E.R. ... 184 (2001) 255
Binns, C., see Finetti, P. ... 184 (2001) 627
Bos, A.J.J., High sensitivity thermoluminescence dosimetry ... 184 (2001) 3
Bower, R.W., see Verda, R.D. ... 184 (2001) 655
Bower, R.W., see Verda, R.D. ... 184 (2001) 656
Bowler, M.A., see Finetti, P. ... 184 (2001) 627
Bradley, P.D., A.B. Rosenfeld and M. Zaider, Solid state microdosimetry ... 184 (2001) 135
Brahme, A., R. Lewensohn, U. Ringborg, U. Amaldi, F. Gerardi and S. Rossi, Design of a centre for biologically optimised light ion therapy in Stockholm ... 184 (2001) 569
Brühwiler, P.A., see Schnadt, J. ... 184 (2001) 609
Burke, E.A., see Xapsos, M.A. ... 184 (2001) 113

Cafarelli, P., see Richard-Viard, M. ... 184 (2001) 490
Carpéna, J., see Soulet, S. ... 184 (2001) 383
Cervera, M., see Barbadillo, L. ... 184 (2001) 361
Chaar, M. and D.E. Watt, Charge transport in liquid tetramethylsilane (TMS) at low and high electric fields ... 184 (2001) 615
Chakravortty, V., see Nayak, P.K. ... 184 (2001) 649
Chandrasekaran, K.S., see Nair, G.P. ... 184 (2001) 515
Chaumont, J., see Soulet, S. ... 184 (2001) 383
Chen, F., see Wang, K.-M. ... 184 (2001) 378
Chen, Y., see Li, D. ... 184 (2001) 500
Cheng, D., see Liu, B. ... 184 (2001) 644

0168-583X/01/S - see front matter © 2001 Published by Elsevier Science B.V. All rights reserved.
PII: S0168-583X(01)00963-6

Chevolleau, T., see Telbizova, T. ... 184 (2001) 347
Chiari, M., L. Giuntini, P.A. Mandò and N. Taccetti, Proton elastic scattering cross-section on boron from 0.5 to 3.3 MeV ... 184 (2001) 309
Chromik, M.J., see Baumann, T. ... 184 (2001) 473
Clement, R.R.C., see Baumann, T. ... 184 (2001) 473

Das, D., see Nayak, P.K. ... 184 (2001) 649
d'Errico, F., Radiation dosimetry and spectrometry with superheated emulsions ... 184 (2001) 229
Desrosiers, M. and D.A. Schauer, Electron paramagnetic resonance (EPR) biodosimetry ... 184 (2001) 219
de Voigt, M.J.A., see Selen, L.J.M. ... 184 (2001) 559

Fakhrai, M., see Lamehi-Rachti, M. ... 184 (2001) 430
Falkenstein, P.L., see Huston, A.L. ... 184 (2001) 55
Finetti, P., D.M.P. Holland, C.J. Latimer, C. Binns, F.M. Quinn, M.A. Bowler, A.F. Grant and C.S. Mythen, A spherical grating monochromator and beamline optimised for the provision of polarised synchrotron radiation in the photon energy range 20–200 eV ... 184 (2001) 627
Freigang, C., see Baumann, T. ... 184 (2001) 473

Gammino, S., see Torrisi, L. ... 184 (2001) 327
Gardès, D., G. Maynard, G. Belyaev and I. Roudskoy, Diagnostics of gas density gradient by swift ions ... 184 (2001) 458
Gerardi, F., see Brahme, A. ... 184 (2001) 569
Giuntini, L., see Chiari, M. ... 184 (2001) 309
Gokhale, M.R., see Nair, G.P. ... 184 (2001) 515
Grant, A.F., see Finetti, P. ... 184 (2001) 627
Grønbech-Jensen, N., see Sillanpää, J. ... 184 (2001) 523
Grötzschel, R., see Kokkoris, M. ... 184 (2001) 319

Hanamoto, K., M. Sasaki, H. Miki and Y. Nakayama, Effects of carbon implantation on the electrical properties of amorphous In_2O_3 thin film ... 184 (2001) 371
He, R., see Liu, B. ... 184 (2001) 644
Heckman, P., see Baumann, T. ... 184 (2001) 473
Hernández, M.J., see Barbadillo, L. ... 184 (2001) 361
Hishita, S., see Hwang, Y. ... 184 (2001) 555
Hoechbauer, T., see Verda, R.D. ... 184 (2001) 656
Holland, D.M.P., see Finetti, P. ... 184 (2001) 627
Horowitz, Y.S., Theory of thermoluminescence gamma dose response: The unified interaction model ... 184 (2001) 68
Horowitz, Y.S., O. Avila and M. Rodriguez-Villafuerte, Theory of heavy charged particle response (efficiency and supralinearity) in TL materials ... 184 (2001) 85
Hu, H., see Wang, K.-M. ... 184 (2001) 378
Huston, A.L., B.L. Justus, P.L. Falkenstein, R.W. Miller, H. Ning and R. Altemus, Remote optical fiber dosimetry ... 184 (2001) 55
Hwang, Y., R. Souda, S. Hishita and S. Otani, Ta segregation at the TiC(0 0 1) surface studied by time-of-flight impact-collision ion scattering spectroscopy ... 184 (2001) 555

Ikeda, Y., see Niita, K. ... 184 (2001) 406

Janssen, F.J.J., see Selen, L.J.M. ... 184 (2001) 559
Jiang, B.-Y., see Zheng, L.-P. ... 184 (2001) 354
Justus, B.L., see Huston, A.L. ... 184 (2001) 55

Kaitasov, O., see Soulet, S. ... 184 (2001) 383
Klintberg, L., M. Lindeberg and G. Thornell, Sodium hypochlorite as a developer for heavy ion tracks in polyimide ... 184 (2001) 536
Kokkoris, M., S. Kossionides, R. Vlastou, X.A. Aslanoglou, R. Grötzschel, B. Nsouli, A. Kuznetsov, S. Petrovic and Th. Paradellis, Determination of parameters for channeling of protons in SiC polytype crystals in the backscattering geometry ... 184 (2001) 319
Koponen, I.T., see Sillanpää, J. ... 184 (2001) 523

Korchev, Yu.E., see Apel, P.Yu. ... 184 (2001) 337
Kossionides, S., see Kokkoris, M. ... 184 (2001) 319
Kovács, Z., see Szelecsényi, F. ... 184 (2001) 589
Kràsa, J., see Torrisi, L. ... 184 (2001) 327
Krupa, J.-C., see Soulet, S. ... 184 (2001) 383
Kuznetsov, A., see Kokkoris, M. ... 184 (2001) 319

Lamehi-Rachti, M., P. Oliaiy, J. Rahighi, F. Shokouhi and M. Fakhrai, Application of PIXRF in the analysis of archaeological glazed tiles ... 184 (2001) 430
Landre-Pellemoine, F., see Maunoury, L. ... 184 (2001) 441
Làska, L., see Torrisi, L. ... 184 (2001) 327
Latimer, C.J., see Finetti, P. ... 184 (2001) 627
Lewensohn, R., see Brahme, A. ... 184 (2001) 569
Li, D., G. Wang, Y. Chen, L. Lin, G. Shrivastav, S. Oak, A. Tasch, S. Banerjee and B. Obradovic, A computationally efficient simulator for three-dimensional Monte Carlo simulation of ion implantation into complex structures ... 184 (2001) 500
Li, D.-X., see Zheng, L.-P. ... 184 (2001) 354
Lichtenthäler, R., see Maunoury, L. ... 184 (2001) 441
Lin, C., see Wan, Q. ... 184 (2001) 531
Lin, L., see Li, D. ... 184 (2001) 500
Lindeberg, M., see Klintberg, L. ... 184 (2001) 536
Liu, B., C. Liu, D. Cheng, G. Zhang, R. He and S.-Z. Yang, A new method for inner surface modification by plasma source ion implantation (PSII) ... 184 (2001) 644
Liu, C., see Liu, B. ... 184 (2001) 644
Liu, W., see Wan, Q. ... 184 (2001) 531
Lu, F., see Wang, K.-M. ... 184 (2001) 378
Lu, Q.-M., see Wang, K.-M. ... 184 (2001) 378

Ma, C.-Q., see Wang, K.-M. ... 184 (2001) 378
Maggiore, C.J., see Verda, R.D. ... 184 (2001) 655
Maggiore, C.J., see Verda, R.D. ... 184 (2001) 656
Mandelis, A., see Mendoza, P.J. ... 184 (2001) 421
Mandò, P.A., see Chiari, M. ... 184 (2001) 309
Mårtensson, N., see Schnadt, J. ... 184 (2001) 609
Mathur, V.K., Ion storage dosimetry ... 184 (2001) 190
Maunoury, L., O. Bajeat, F. Landre-Pellemoine, R. Lichtenthäler and A.C.C. Villari, Temperature simulations of high power graphite targets for heavy ions ... 184 (2001) 441
Maynard, G., see Gardès, D. ... 184 (2001) 458
McKeever, S.W.S., see Moscovitch, M. ... 184 (2001) 1
McKeever, S.W.S., Optically stimulated luminescence dosimetry ... 184 (2001) 29
Meigo, S.-i., see Niita, K. ... 184 (2001) 406
Mendoza, P.J., see Rodríguez, M.E. ... 184 (2001) 421
Menna, M., ISOL beam intensities of ^{7}Be, ^{18}F, ^{22,24}Na obtained in the reaction: ^{19}F (48MeV/amu) + ^{12}C ... 184 (2001) 466
Miki, H., see Hanamoto, K. ... 184 (2001) 371
Miller, R.W., see Huston, A.L. ... 184 (2001) 55
Misra, A., see Verda, R.D. ... 184 (2001) 656
Molina, S.I., see Barbadillo, L. ... 184 (2001) 361
Möller, W., see Telbizova, T. ... 184 (2001) 347
Morales, F.M., see Barbadillo, L. ... 184 (2001) 361
Moscovitch, M. and S.W.S. McKeever, Editorial ... 184 (2001) 1
Moscovitch, M. and G.W. Phillips, Radiation dosimetry using three-dimensional optical random access memories ... 184 (2001) 207
Mythen, C.S., see Finetti, P. ... 184 (2001) 627

Nair, G.P., K.S. Chandrasekaran, A.M. Narsale, B.M. Arora and M.R. Gokhale, High resolution XRD study of GaAs implanted with 50 MeV ^{120}Sn ions ... 184 (2001) 515
Nakayama, Y., see Hanamoto, K. ... 184 (2001) 371

Narsale, A.M., see Nair, G.P. ... 184 (2001) 515
Nastasi, M., see Verda, R.D. ... 184 (2001) 655
Nastasi, M., see Verda, R.D. ... 184 (2001) 656
Nayak, P.K., D. Das, V. Vijayan, P. Singh and V. Chakravortty, ^{57}Fe Mössbauer and EDXRF studies on three representative banded iron formations (BIFs) of Orissa, India ... 184 (2001) 649
Nicolaides, L., see Mendoza, P.J. ... 184 (2001) 421
Niita, K., H. Takada, S.-i. Meigo and Y. Ikeda, High-energy particle transport code NMTC/JAM ... 184 (2001) 406
Ning, H., see Huston, A.L. ... 184 (2001) 55
Nsouli, B., see Kokkoris, M. ... 184 (2001) 319

Oak, S., see Li, D. ... 184 (2001) 500
Obiajunwa, E.I., Analysis of some Nigerian solid mineral ores by energy-dispersive X-ray fluorescence spectroscopy ... 184 (2001) 437
Obradovic, B., see Li, D. ... 184 (2001) 500
Okada, K., see Szelecsényi, F. ... 184 (2001) 589
Oliaiy, P., see Lamehi-Rachti, M. ... 184 (2001) 430
O'Shea, J.N., see Schnadt, J. ... 184 (2001) 609
Otani, S., see Hwang, Y. ... 184 (2001) 555

Paradellis, Th., see Kokkoris, M. ... 184 (2001) 319
Patthey, L., see Schnadt, J. ... 184 (2001) 609
Petrovic, S., see Kokkoris, M. ... 184 (2001) 319
Phillips, G.W., see Moscovitch, M. ... 184 (2001) 207
Piqueras, J., see Barbadillo, L. ... 184 (2001) 361
Poivey, C., see Xapsos, M.A. ... 184 (2001) 113
Puglia, C., see Schnadt, J. ... 184 (2001) 609

Qiu, S., see Zheng, L.-P. ... 184 (2001) 354
Quinn, F.M., see Finetti, P. ... 184 (2001) 627

Rahighi, J., see Lamehi-Rachti, M. ... 184 (2001) 430
Richardson, L.M., see Wagner, H.W. ... 184 (2001) 450
Richard-Viard, M., S. Abidi, C. Bénazeth, P. Benoit-Cattin and P. Cafarelli, Azimuthal dependence of charge exchange in grazing scattering of 4 keV ions on a NaCl(1 0 0) surface: Role of the trajectory ... 184 (2001) 490
Ringborg, U., see Brahme, A. ... 184 (2001) 569
Rodríguez, M.E., P.J. Mendoza, A. Mandelis and L. Nicolaides, Combined photothermal and photoacoustic characterization of silicon–epoxy composites and the existence of a particle thermal percolation threshold. ... 184 (2001) 421
Rodríguez, P., see Barbadillo, L. ... 184 (2001) 361
Rodriguez-Villafuerte, M., see Horowitz, Y.S. ... 184 (2001) 85
Rosenfeld, A.B., see Bradley, P.D. ... 184 (2001) 135
Rossi, S., see Brahme, A. ... 184 (2001) 569
Roudskoy, I., see Gardès, D. ... 184 (2001) 458
Ruault, M.-O., see Soulet, S. ... 184 (2001) 383

Sasaki, M., see Hanamoto, K. ... 184 (2001) 371
Schauer, D.A., see Desrosiers, M. ... 184 (2001) 219
Schiessling, J., see Schnadt, J. ... 184 (2001) 609
Schnadt, J., J. Schiessling, J.N. O'Shea, L. Patthey, M. Shi, C. Puglia, N. Mårtensson and P.A. Brühwiler, Beamline-induced chromium structure in carbon K-edge absorption spectra ... 184 (2001) 609
Seitz, J.P., see Baumann, T. ... 184 (2001) 473
Selen, L.J.M., F.J.J. Janssen, L.J. van IJzendoorn, M.J.A. de Voigt, P.J.M. Smulders and M.J.J. Theunissen, Planar ion-channeling measurements on buried nano-films ... 184 (2001) 559
Shen, D.-Y., see Wang, K.-M. ... 184 (2001) 378
Sherrill, B.M., see Baumann, T. ... 184 (2001) 473
Shevelko, V.P., I.Yu. Tolstikhina and Th. Stöhlker, Stripping of fast heavy low-charged ions in gaseous targets ... 184 (2001) 295
Shi, B.-R., see Wang, K.-M. ... 184 (2001) 378

Shi, M., see Schnadt, J. ... 184 (2001) 609
Shokouhi, F., see Lamehi-Rachti, M. ... 184 (2001) 430
Shrivastav, G., see Li, D. ... 184 (2001) 500
Sillanpää, J., I.T. Koponen and N. Grønbech-Jensen, A rate-equation model for the growth of metallic thin films in ion beam assisted deposition ... 184 (2001) 523
Singh, P., see Nayak, P.K. ... 184 (2001) 649
Siwy, Z., see Apel, P.Yu. ... 184 (2001) 337
Smulders, P.J.M., see Selen, L.J.M. ... 184 (2001) 559
Souda, R., see Hwang, Y. ... 184 (2001) 555
Soulet, S., J. Carpéna, J. Chaumont, O. Kaitasov, M.-O. Ruault and J.-C. Krupa, Simulation of the α-annealing effect in apatitic structures by He-ion irradiation: Influence of the silicate/phosphate ratio and of the OH^-/F^- substitution ... 184 (2001) 383
Spohr, R., see Apel, P.Yu. ... 184 (2001) 337
Stöhlker, Th., see Shevelko, V.P. ... 184 (2001) 295
Störi, H., see Wagner, H.W. ... 184 (2001) 450
Summers, G.P., see Xapsos, M.A. ... 184 (2001) 113
Suzuki, K., see Szelecsényi, F. ... 184 (2001) 589
Szelecsényi, F., K. Suzuki, Z. Kovács, M. Takei and K. Okada, Alpha beam monitoring via ^{nat}Cu+alpha processes in the energy range from 40 to 60 MeV ... 184 (2001) 589

Taccetti, N., see Chiari, M. ... 184 (2001) 309
Takada, H., see Niita, K. ... 184 (2001) 406
Takei, M., see Szelecsényi, F. ... 184 (2001) 589
Takeuchi, T., see Yonehara, K. ... 184 (2001) 391
Takeuchi, W. and Y. Yamamura, Structure analysis of insulator KBr(1 0 0) surface by three-dimensional computer simulation of NICASS ... 184 (2001) 544
Tamboul, J.Y. and D.E. Watt, A proportional counter for measurement of the bio-effectiveness of ionising radiations at the DNA level ... 184 (2001) 597
Tanaka, M., see Yonehara, K. ... 184 (2001) 391
Tasch, A., see Li, D. ... 184 (2001) 500
Telbizova, T., T. Chevolleau and W. Möller, Nitrogen incorporation and loss during ion nitriding of Al ... 184 (2001) 347
Tesmer, J.R., see Verda, R.D. ... 184 (2001) 655
Tesmer, J.R., see Verda, R.D. ... 184 (2001) 656
Theunissen, M.J.J., see Selen, L.J.M. ... 184 (2001) 559
Thoennessen, M., see Baumann, T. ... 184 (2001) 473
Thornell, G., see Klintberg, L. ... 184 (2001) 536
Tolstikhina, I.Yu., see Shevelko, V.P. ... 184 (2001) 295
Torrisi, L., L. Andò, S. Gammino, J. Kràsa and L. Làska, Ion and neutral emission from pulsed laser irradiation of metals ... 184 (2001) 327
Tryggestad, E.J., see Baumann, T. ... 184 (2001) 473

van IJzendoorn, L.J., see Selen, L.J.M. ... 184 (2001) 559
Verda, R.D., J.R. Tesmer, C.J. Maggiore, M. Nastasi and R.W. Bower, Erratum to "Geometric considerations relevant to hydrogen depth profiling by reflection elastic recoil detection analysis" [Nucl. Instr. and Meth. B. 183 (2001) 391-400] ... 184 (2001) 655
Verda, R.D., C.J. Maggiore, J.R. Tesmer, A. Misra, T. Hoechbauer, M. Nastasi and R.W. Bower, Erratum to "Depth profiling of hydrogen in crystalline silicon using elastic recoil detection analysis" [Nucl. Instr. and Meth. B. 183 (2001) 401-412] ... 184 (2001) 656
Vijayan, V., see Nayak, P.K. ... 184 (2001) 649
Villari, A.C.C., see Maunoury, L. ... 184 (2001) 441
Vlastou, R., see Kokkoris, M. ... 184 (2001) 319

Wagner, H.W., W.S.M. Werner, H. Störi and L.M. Richardson, Electron probe microanalysis inverse modeling ... 184 (2001) 450
Wan, Q., L. Wang, W. Liu, M. Zhang and C. Lin, Investigation of H^+ and B^+/H^+ implantation in $LiTaO_3$ single-crystals ... 184 (2001) 531
Wang, G., see Li, D. ... 184 (2001) 500

Wang, K.-M., H. Hu, F. Chen, F. Lu, B.-R. Shi, C.-Q. Ma, Q.-M. Lu and D.-Y. Shen, Refractive index profile of waveguide in $NdLiP_4O_{12}$ laser crystal formed by MeV He^+ ion implantation 184 (2001) 378
Wang, L., see Wan, Q. 184 (2001) 531
Watt, D.E., see Tamboul, J.Y. 184 (2001) 597
Watt, D.E., see Chaar, M. 184 (2001) 615
Werner, W.S.M., see Wagner, H.W. 184 (2001) 450
Wu, Y., see Zhang, T. 184 (2001) 509

Xapsos, M.A., G.P. Summers, E.A. Burke and C. Poivey, Microdosimetry theory for microelectronics applications 184 (2001) 113

Yamagata, T., see Yonehara, K. 184 (2001) 391
Yamamura, Y., see Takeuchi, W. 184 (2001) 544
Yang, S.-Z., see Liu, B. 184 (2001) 644
Yonchara, K., T. Yamagata, Y. Arimoto, T. Takeuchi and M. Tanaka, Relaxation mechanism of optically pumped Rb vapor of high density in strong magnetic fields. 184 (2001) 391
Yoshida, M., see Apel, P.Yu. 184 (2001) 337

Zaider, M., see Bradley, P.D. 184 (2001) 135
Zhang, G., see Liu, B. 184 (2001) 644
Zhang, Y., see Zhang, T. 184 (2001) 509
Zhang, M., see Wan, Q. 184 (2001) 531
Zhang, S.-Z., see Liu, B 184 (2001) 644
Zhang, T., Y. Wu and Y. Zhang, Formation and behavior of ceramic layer by ion-deposited Ti coating using FMEVAD and Ti and C dual-implantation 184 (2001) 509
Zheng, L.-P., D.-X. Li, S. Qiu, W.-J. Zhou and B.-Y. Jiang, Dependence of Ni, Al and B boundary concentrations on the B bulk concentration for the Ni_3Al–x at.% B grain boundary 184 (2001) 354
Zhou, W.-J., see Zheng, L.-P. 184 (2001) 354

Nuclear Instruments and Methods in Physics Research B 184 (2001) 667–669

ELSEVIER

NIM B
Beam Interactions with Materials & Atoms

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Subject index

Basic Data for Materials Modifications and Analysis

Stripping of fast heavy low-charged ions in gaseous targets, V.P. Shevelko, I.Yu. Tolstikhina and Th. Stöhlker 184 (2001) 295
Proton elastic scattering cross-section on boron from 0.5 to 3.3 MeV, M. Chiari, L. Giuntini, P.A. Mandò and N. Taccetti . . . 184 (2001) 309
Catching energetic heavy-ion beams in gas, T. Baumann, M.J. Chromik, R.R.C. Clement, C. Freigang, P. Heckman, J.P. Seitz, B.M. Sherrill, M. Thoennessen and E.J. Tryggestad . . . 184 (2001) 473

Atomic Collisions in solids

Determination of parameters for channeling of protons in SiC polytype crystals in the backscattering geometry, M. Kokkoris, S. Kossionides, R. Vlastou, X.A. Aslanoglou, R. Grötzschel, B. Nsouli, A. Kuznetsov, S. Petrovic and Th. Paradellis . . . 184 (2001) 319
Ion and neutral emission from pulsed laser irradiation of metals, L. Torrisi, L. Andò, S. Gammino, J. Kràsa and L. Làska . . . 184 (2001) 327
A new model for electron ranges in solid materials, J.E. Bateman . . . 184 (2001) 478
Azimuthal dependence of charge exchange in grazing scattering of 4 keV ions on a NaCl(1 0 0) surface: Role of the trajectory, M. Richard-Viard, S. Abidi, C. Bénazeth, P. Benoit-Cattin and P. Cafarelli . . . 184 (2001) 490

Ion Beam Modification of Materials

Diode-like single-ion track membrane prepared by electro-stopping, P.Yu. Apel, Yu.E. Korchev, Z. Siwy, R. Spohr and M. Yoshida . . . 184 (2001) 337
Nitrogen incorporation and loss during ion nitriding of Al, T. Telbizova, T. Chevolleau and W. Möller . . . 184 (2001) 347
Dependence of Ni, Al and B boundary concentrations on the B bulk concentration for the Ni_3Al–x at.% B grain boundary, L.-P. Zheng, D.-X. Li, S. Qiu, W.-J. Zhou and B.-Y. Jiang . . . 184 (2001) 354
Structural characterization of high-dose $C^+ + N^+$ ion-implanted (1 1 1) Si, L. Barbadillo, M.J. Hernández, M. Cervera, P. Rodríguez, J. Piqueras, S.I. Molina, F.M. Morales and D. Araújo . . . 184 (2001) 361
Effects of carbon implantation on the electrical properties of amorphous In_2O_3 thin film, K. Hanamoto, M. Sasaki, H. Miki and Y. Nakayama . . . 184 (2001) 371
Refractive index profile of waveguide in $NdLiP_4O_{12}$ laser crystal formed by MeV He^+ ion implantation, K.-M. Wang, H. Hu, F. Chen, F. Lu, B.-R. Shi, C.-Q. Ma, Q.-M. Lu and D.-Y. Shen . . . 184 (2001) 378
A computationally efficient simulator for three-dimensional Monte Carlo simulation of ion implantation into complex structures, D. Li, G. Wang, Y. Chen, L. Lin, G. Shrivastav, S. Oak, A. Tasch, S. Banerjee and B. Obradovic . . . 184 (2001) 500
Formation and behavior of ceramic layer by ion-deposited Ti coating using FMEVAD and Ti and C dual-implantation, T. Zhang, Y. Wu and Y. Zhang . . . 184 (2001) 509
High resolution XRD study of GaAs implanted with 50 MeV ^{120}Sn ions, G.P. Nair, K.S. Chandrasekaran, A.M. Narsale, B.M. Arora and M.R. Gokhale . . . 184 (2001) 515
A rate-equation model for the growth of metallic thin films in ion beam assisted deposition, J. Sillanpää, I.T. Koponen and N. Grønbech-Jensen . . . 184 (2001) 523
Investigation of H^+ and B^+/H^+ implantation in $LiTaO_3$ single-crystals, Q. Wan, L. Wang, W. Liu, M. Zhang and C. Lin . . . 184 (2001) 531

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Effects of Radiation

Simulation of the α-annealing effect in apatitic structures by He-ion irradiation: Influence of the silicate/phosphate ratio and of the OH^-/F^- substitution, S. Soulet, J. Carpéna, J. Chaumont, O. Kaitasov, M.-O. Ruault and J.-C. Krupa . . . 184 (2001) 383
Relaxation mechanism of optically pumped Rb vapor of high density in strong magnetic fields, K. Yonehara, T. Yamagata, Y. Arimoto, T. Takeuchi and M. Tanaka . . . 184 (2001) 391
High-energy particle transport code NMTC/JAM, K. Niita, H. Takada, S.-i. Meigo and Y. Ikeda . . . 184 (2001) 406
Sodium hypochlorite as a developer for heavy ion tracks in polyimide, L. Klintberg, M. Lindeberg and G. Thornell . . . 184 (2001) 536

Analysis of Materials

Combined photothermal and photoacoustic characterization of silicon–epoxy composites and the existence of a particle thermal percolation threshold, M.E. Rodríguez, P.J. Mendoza, A. Mandelis and L. Nicolaides . . . 184 (2001) 421
Application of PIXRF in the analysis of archaeological glazed tiles, M. Lamehi-Rachti, P. Oliaiy, J. Rahighi, F. Shokouhi and M. Fakhrai . . . 184 (2001) 430
Analysis of some Nigerian solid mineral ores by energy-dispersive X-ray fluorescence spectroscopy, E.I. Obiajunwa . . . 184 (2001) 437
Structure analysis of insulator KBr(1 0 0) surface by three-dimensional computer simulation of NICASS, W. Takeuchi and Y. Yamamura . . . 184 (2001) 544
Ta segregation at the TiC(0 0 1) surface studied by time-of-flight impact-collision ion scattering spectroscopy, Y. Hwang, R. Souda, S. Hishita and S. Otani . . . 184 (2001) 555
Planar ion-channeling measurements on buried nano-films, L.J.M. Selen, F.J.J. Janssen, L.J. van IJzendoorn, M.J.A. de Voigt, P.J.M. Smulders and M.J.J. Theunissen . . . 184 (2001) 559
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Ion Sources and Beam Optics

Temperature simulations of high power graphite targets for heavy ions, L. Maunoury, O. Bajeat, F. Landre-Pellemoine, R. Lichtenthäler and A.C.C. Villari . . . 184 (2001) 441

Experimental Methods and Equipment

Editorial, M. Moscovitch and S.W.S. McKeever . . . 184 (2001) 1
High sensitivity thermoluminescence dosimetry, A.J.J. Bos . . . 184 (2001) 3
Optically stimulated luminescence dosimetry, S.W.S. McKeever . . . 184 (2001) 29
Remote optical fiber dosimetry, A.L. Huston, B.L. Justus, P.L. Falkenstein, R.W. Miller, H. Ning and R. Altemus . . . 184 (2001) 55
Theory of thermoluminescence gamma dose response: The unified interaction model, Y.S. Horowitz . . . 184 (2001) 68
Theory of heavy charged particle response (efficiency and supralinearity) in TL materials, Y.S. Horowitz, O. Avila and M. Rodriguez-Villafuerte . . . 184 (2001) 85
Microdosimetry theory for microelectronics applications, M.A. Xapsos, G.P. Summers, E.A. Burke and C. Poivey . . . 184 (2001) 113
Solid state microdosimetry, P.D. Bradley, A.B. Rosenfeld and M. Zaider . . . 184 (2001) 135
Electronic dosimeters based on solid state detectors, J. Barthe . . . 184 (2001) 158
Ion storage dosimetry, V.K. Mathur . . . 184 (2001) 190
Radiation dosimetry using three-dimensional optical random access memories, M. Moscovitch and G.W. Phillips 184 (2001) 207
Electron paramagnetic resonance (EPR) biodosimetry, M. Desrosiers and D.A. Schauer . . . 184 (2001) 219
Radiation dosimetry and spectrometry with superheated emulsions, F. d'Errico . . . 184 (2001) 229
Space radiation dosimetry in low-Earth orbit and beyond, E.R. Benton and E.V. Benton . . . 184 (2001) 255
Electron probe microanalysis inverse modeling, H.W. Wagner, W.S.M. Werner, H. Störi and L.M. Richardson 184 (2001) 450
Diagnostics of gas density gradient by swift ions, D. Gardès, G. Maynard, G. Belyaev and I. Roudskoy . . . 184 (2001) 458

Design of a centre for biologically optimised light ion therapy in Stockholm, A. Brahme, R. Lewensohn, U. Ringborg, U. Amaldi, F. Gerardi and S. Rossi 184 (2001) 569
Alpha beam monitoring via ^{nat}Cu+alpha processes in the energy range from 40 to 60 MeV, F. Szelecsényi, K. Suzuki, Z. Kovács, M. Takei and K. Okada 184 (2001) 589
A proportional counter for measurement of the bio-effectiveness of ionising radiations at the DNA level, J.Y. Tamboul and D.E. Watt 184 (2001) 597
Beamline-induced chromium structure in carbon K-edge absorption spectra, J. Schnadt, J. Schiessling, J.N. O'Shea, L. Patthey, M. Shi, C. Puglia, N. Mårtensson and P.A. Brühwiler 184 (2001) 609
Charge transport in liquid tetramethylsilane (TMS) at low and high electric fields, M. Chaar and D.E. Watt . . 184 (2001) 615
A spherical grating monochromator and beamline optimised for the provision of polarised synchrotron radiation in the photon energy range 20–200 eV, P. Finetti, D.M.P. Holland, C.J. Latimer, C. Binns, F.M. Quinn, M.A. Bowler, A.F. Grant and C.S. Mythen. 184 (2001) 627
A new method for inner surface modification by plasma source ion implantation (PSII), B. Liu, C. Liu, D. Cheng, G. Zhang, R. He and S.-Z. Yang. 184 (2001) 644

Letters to the Editors

ISOL beam intensities of ^{7}Be, ^{18}F, ^{22,24}Na obtained in the reaction: ^{19}F (48MeV/amu) + ^{12}C, M. Menna 184 (2001) 466
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Errata

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Erratum to Cover of Volume 184, Nos. 1–2,. 184 (2001) 657